

ALMA MATER STUDIORUM Università di Bologna







# Modeling the Electric Switching of Chalcogenide Materials Below the Nanoscale Limit

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## Chalcogenides

Chemical compounds consisting of at least one chalcogen ion (S, Se, or Te), and one or more electropositive elements:

#### GeTe, Ge<sub>2</sub>Sb<sub>2</sub>Te<sub>5</sub>, ZnTe, AgInSbTe (AIST), ...



They yield (binary, ternary,...) alloys with semiconductor properties.



Concept first proposed by S. Ovshinsky (1922-2012) in 1968.

#### *I(V)* characteristic: threshold-switching behavior



### Threshold-switching: useful properties



Resistivity changes by at least 2 orders of magnitude

Stability of the two physical states, and large duty cycle.

- Large difference in physical properties (resistivity, reflectivity) between the two (crystalline and amorphous) phases.
- **Two-state system**: possibility to store logic information («0» or «1»).
- Fast (down to few ns) and reversible transition between amorph. (OFF and ON) and crystalline phases induced by heating (laser irradiation or Joule effect).

## Application to memories and research issues





D-C. Kau et al., 2009 IEDM Tech. Digest, 617

Optane: non-volatile memory commercialised by Micron-Intel in 2017

# The origin (electrical, thermal or mixed electrical/thermal) of the Ovonic Switch is still a debated issue

## Switching of the *a*-phase triggered by carrier heating

- Localized (trap) and mobile (band) states in the amorphous phase.
- Energy transfer from an external field to charge carriers.
  - $\Delta~$  is known from optical measurements

The dispersion relation is condensed into parameter  $g_T / g_B$ 



Near threshold, carrier heating gives rise to a positive feedback by inducing transitions to mobile states: this determines the transition (OTS) to the low-resistivity, stillamorphous, phase. Key features of the model – A: hydrodynamic equations Trap-limited transport, i.e., field-assisted (Poole) transitions between localized and mobile states. The number of electrons is large enough to allow for a continuous description

$$\frac{\partial n}{\partial t} + \frac{1}{q} \frac{\partial J}{\partial z} = 0$$
$$\frac{\partial n_B}{\partial t} = \frac{\partial n}{\partial t} - \frac{n_B - \tilde{n}_B}{\tau_n}$$
$$\frac{\partial \epsilon_{\text{tot}}}{\partial t} = JF - \frac{\Delta}{q} \frac{\partial J}{\partial z} - \frac{k_B}{q} \frac{T_e - T_0}{\tau_T}$$
$$\frac{\partial F}{\partial z} = -\frac{q}{\varepsilon} [n - n_{\text{eq}}]$$

Particle continuity

Local particle redistribution

**Energy continuity** 

Poisson eq.

## Key features of the model – B

- Nanometric, homogeneous block of amorphous chalcogenide, with unipolar (electron) conduction.
- Localised and mobile states; field-assisted (Poole) transitions.
- Electrons tend to the Fermi distribution at temperature  $T_e$
- Equilibrium conditions at the injecting (ohmic) contact, spatial homogeneity found at the exit side (see next slide).

## Spatial (in)homogeneity

In steady state, spatial inhomogeneity is found close to the injection contact.



Key features of the model – C: Numerical solution

- Forward Euler method. The complicacy of the model dictates a small integration step ( $\Delta t = 10^{-16}$  s).
- No numerical instability detected during the simulations; in fact, time constants in the model have little interplay:
  - $\circ$   $\tau_T$  (ps) dominates up to threshold
  - $\circ$   $\tau_n$  (ns) controls the population relaxation
- Accuracy of about 10% is considered appropriate to compare simulation with experimental data.

Transport Aspects investigated with the model (2012-23)

- Electrical nature of OTS in chalcogenides demonstrated (Piccinini *et al.,* JAP 2012).
- Dynamics of the electron heating and the OTS onset analyzed (Cappelli *et al.*, APL 2013).
- Time-dependent operation including parasitics effect (Piccinini *et al.*, J. Phys. D, 2016).
- Role of the dispersion of the band states (Brunetti *et al.,* JCE 2020).
- Electric response in presence of a time-dependent bias (Brunetti *et al.*, Frontiers in Physics, 2022).
- This work: comparison of transient regimes in different chalcogenides (GST-225, ZnTe, AIST) at room and high temperatures; useful for, e.g., automotive applications.

#### Search for the "static" threshold voltage for OTS

Transient towards stationarity after the application of a voltage step. Estimated accuracy  $\sim 10\%$ , time span  $\sim 3$  ns.



### Experimental data about ultrafast transient regimes

- Advanced programmable setup for electrical tests (time resolution ~50 ps, rise/fall times of the pulse ~ 1 ns, pulse width ≤ 1.5 ns, pulse plateu > V<sub>th</sub>).
  Shukla et al., (2017), Rev. Sci. Instrum.
- Threshold switching in the ps range demonstrated in AgInSbTe (AIST) cells and as short as 1 ns in GST 225 cells.

Shukla et al., (2016) Sci. Rep. 6, 37868 (AIST)

Zalden et.al., (2016) Phys. Rev. Letters (AIST)

Saxena et al., (2021) Sci. Rep. 11, 6111 (GST-225)

#### Experimental data about ultrafast transient regimes

Ramp voltage with finite ( $\sim$ ns) rise and fall times: threshold switching dynamics below the ns scale found in GST-225.



#### Transport dynamics: GST 225 ( $T_c \cong 420 \text{ K}$ )



### Transport dynamics: ZnTe ( $T_c \cong 380$ K), AIST ( $T_c \cong 450$ K)



#### Estimate of the delay time

 $\tau_D$  = interval between the instant when the applied voltage exceeds  $V_{\rm th}$  and the instant when the device current rises steeply.



#### Delay-time – GST 225 at different plateaux



#### Delay-time – ZnTe, GST 225, AIST



## Conclusions

- Hydrodynamic-like transport model for amorphous chalcogenides tested against experiments with voltages varying in the ns scale.
- Increase in lattice temperature reduces  $V_{\rm th}$  and  $\tau_D$ .
- ZnTe has the longest  $\tau_D$ .
- GST confirmed as best performing at high temperatures. Moderate change of  $V_{\rm th}$  and  $\tau_D$ .
- AIST shows a strong decrease of  $\tau_D$  at higher *T*, together with the maximum  $V_{th}$  decrease.